INFORMATION DISCLOSURE CITATION				Atty Docket: 061450/0304605		Serial No.	
PTO-1449				FID-101-D1		to be assigned	
Applicant: S. Prakash							
Submitted: July 3, 2003				Filing Date: Herewith		Prior Group Art Unit: 2856	
EXAMINER'S			NAME				FILING DATE
INITIALS	PATENT NO.	03 Mar 1998	NAME Hellemans et al.		CLASS 324	SUBCLASS 719	06/25/96
Re	5,723,981		Green et al.		73	105	06/25/96
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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY		CLASS		Translation
							Yes No
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	OTHERIDOCU	JMENTS (Incl	udingAt	thor Title Date: Pertine	int Page	s Etc.)	
OTHERIDOCUMENTS (Including Author Title Date; Pertinent Pages, Etc.) De Wolf, et al. "Lateral and vertical dopant profiling in semiconductors by atomic force microscopy using							
RR	conducting tops" (J. Vac. Sci. Tech. A 13(3), May/June 1995, pp. 1699-1704						
							
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EXAMINER RAEVIS				DATE CONSIDERED	2 - 5	5-04	-

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.